Customer No. 22,852
Attorney Docket No. 04208.0245

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:
PCT/JP2005/06840

Akira UMEDA

Application No.: 10/594,317

Filed: August 17, 2007

For: METHOD OF MEASURING TRANSVERSE SENSITIVITY OF SENSOR FOR DETECTING ACCELERATION AND ACCELERATION MEASURING METHOD

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§1.56 and 1.97(b), applicant brings to the Examiner's attention the documents listed on the attached Form PTO/SB/08. Copies of the listed foreign patent documents are attached. Applicant respectfully requests that the Examiner consider the documents listed on attached Form PTO/SB/08 and indicate that they were considered by making an appropriate notation on this form.

This Information Disclosure Statement is being filed with the above-referenced application.

The following are listed on the accompanying PTO/SB/08 and are in a non-English language:

1. Japanese Patent Application Publication No 2000-338128.

2. Akira UMEDA *et al.*, "Revisit the Calibration of Inertia Sensors", The Transactions E of the Institute of Electrical Engineers of Japan, vol. 125, pp. 108-117, (2005).

3. Akira UMEDA *et al.*, " Calibration of three-axis accelerometers using a three-dimensional vibration generator and three laser interferometers" SENSORS AND ACTUATORS A, pp. 93-101, (2004).

4. Akira UMEDA *et al.*, " Calibration of Three-axis Accelerometers as a Three-Dimensional Accelerometer Using a Three-Dimensional Vibration Generator and Laser Interferometers, Metrology Institute of Japan, National Institute of Advanced Industrial Science and Technology, pp. 38-45, (2004).

An English-language abstract of each document listed above is enclosed.

Also enclosed is an English-language international search report from the Japanese Patent Office in the PCT international application, from which this national phase U.S. application is derived, citing documents 1 and 2 above and setting forth the relevance thereof.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed documents are material or constitute "prior art." If the Examiner applies the documents as prior art against any claim in the application and applicant determines that the cited documents do not constitutes "prior art" under United States law, applicant reserves the right to present to the Office the relevant facts and law regarding the appropriate status of such

documents. Applicant further reserves the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should the document be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Dated: August 17, 2007

By: _____
Ernest F. Chapman
Reg. No. 25,961

Enclosures
DWH/FPD/sem

IDS Form PTO/SB/08: Substitute for form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				*Application Number*	10/594,317
				Filing Date	September 27, 2006
				First Named Inventor	Akira UMEDA
				Art Unit	
(Use as many sheets as necessary)				*Examiner Name*	
Sheet	1	of	1	*Attorney Docket Number*	04208.0245

U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials*	Cite No.[1]	Document Number Number-Kind Code[2] *(if known)*	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

Note: Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No.[1]	Foreign Patent Document Country Code[3] Number[4] Kind Code[5] *(if known)*	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation[6]
		JP 2000-338128	12-08-2000	H. Takahashi *et al.*		Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation[6]
		ISO5347-11:1993(E), "Methods for the calibration of vibration and shock pick-ups - Part 11: Testing of transverse vibration sensitivity", International Standard, pp. 296-297, (1993)	
		ISO16063-11:1999(E),"Methods for the calibration of vibration and shock transducers - Part 11: Primary vibration calibration by laser interferometry", International Standard, pp. iii-iv and 1-27, (1999)	
		ISO 5347-1:1993(E), "Methods for the calibration of vibration and shock pick-ups - Part 1: Primary vibration calibration by laser interferometry", International Standard, pp. 233-245, (1993)	
		ISO 2041 : 1990 (E/F), "Vibration and Shock - Vocabulary", International Standard", pp. 47-105, (1990)	
		Akira UMEDA *et al.*, "Revisit the Calibration of Inertia Sensors", The Transactions E of the Institute of Electrical Engineers of Japan, vol. 125, pp. 108-117, (2005)	Abstract
		Akira UMEDA *et al.*, " Calibration of three-axis accelerometers using a three-dimensional vibration generator and three laser interferometers", SENSORS AND ACTUATORS A, pp.93-101, (2004)	Abstract
		Akira UMEDA *et al.*, " Calibration of Three-axis Accelerometers as a Three-Dimensional Accelerometer Using a Three-Dimensional Vibration Generator and Laser Interferometers, Metrology Institute of Japan, National Institute of Advanced Industrial Science and Technology, pp. 38-45, (2004)	Abstract

Examiner Signature		Date Considered	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.